Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/632,665	HAPARNAS ET AL.	
Examiner	Art Unit	
Shin-Hon Chen	2131	

SEARCHED					
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED					
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SEARCH NO (INCLUDING SEARC		
	DATE	EXMR
USPAT, PGPUB, EPO, JPO, DERWENT (BRS search)	7/5/2006	S.C.